
Surface Treatment of Two-Dimensional $Ti_3C_2T_x$ Using Radio-Frequency Remote Plasma System

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Two-dimensional transition metal carbide and/or nitride (MXene) have attracted much attention due to its unique structure and outstanding physical properties such as high electrical conductivity, large surface area and various chemical functionalities. It realizes the potential for future applications including energy storage, electronics, gas or biological sensors and membranes.[1] The MXenes are synthesized through selective etching of A-elements from MAX phases by wet etching process. However, the high sensitive surface properties of MXene give rise to formation of surface terminations (-O, -OH, and -F) during etching process which have been predicted to be directly responsible for various material properties.[2,3] Furthermore, it causes to accelerate the oxidation of MXenes in not only operating environment of various MXene-based devices but also general environment. Therefore, the tuning of surface terminations and reduction of MXenes is necessary to realize the future applications.

We demonstrate the surface treatment of MXene using RF remote plasma system. Two-dimensional titanium carbide ($Ti_3C_2T_x$) was prepared by selective Al interlayer etching of Ti_3AlC_2 using lithium fluoride (LiF) and hydrochloric acid. The $Ti_3C_2T_x$ was exposure to H_2 plasma using a RF remote plasma system. In this system, the plasma generator and the substrate holder are vertically arranged. The sample was located on grounded substrate holder to minimize the effect of ion bombardment. The H_2 plasma was ignited to perform the surface treatment of $Ti_3C_2T_x$. The effect of plasma surface treatment on the change of surface terminations and electrical properties of $Ti_3C_2T_x$ was investigated by adjusting the plasma power, process pressure and exposure time.

Reference

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[2] O. Mashtalir et al., *Nat. Commun.*, 4 (2013) 1716.

[3] M. A. Hope et al., *Phys. Chem. Chem. Phys.*, 18(2016) 5099.